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| Notice of References Cited | Application/Control No. 09/863,861 | | Applicant(s)/Patent Under Reexamination VINJE, VETLE | |
| | Examiner Toan M Le | | Art Unit 2862 | Page 1 of 1 |

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| | C | US- | | | |
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.